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Direct Nanoparticle Printing of CL-20 Using Ultrafast Laser Irradiation

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Abstract

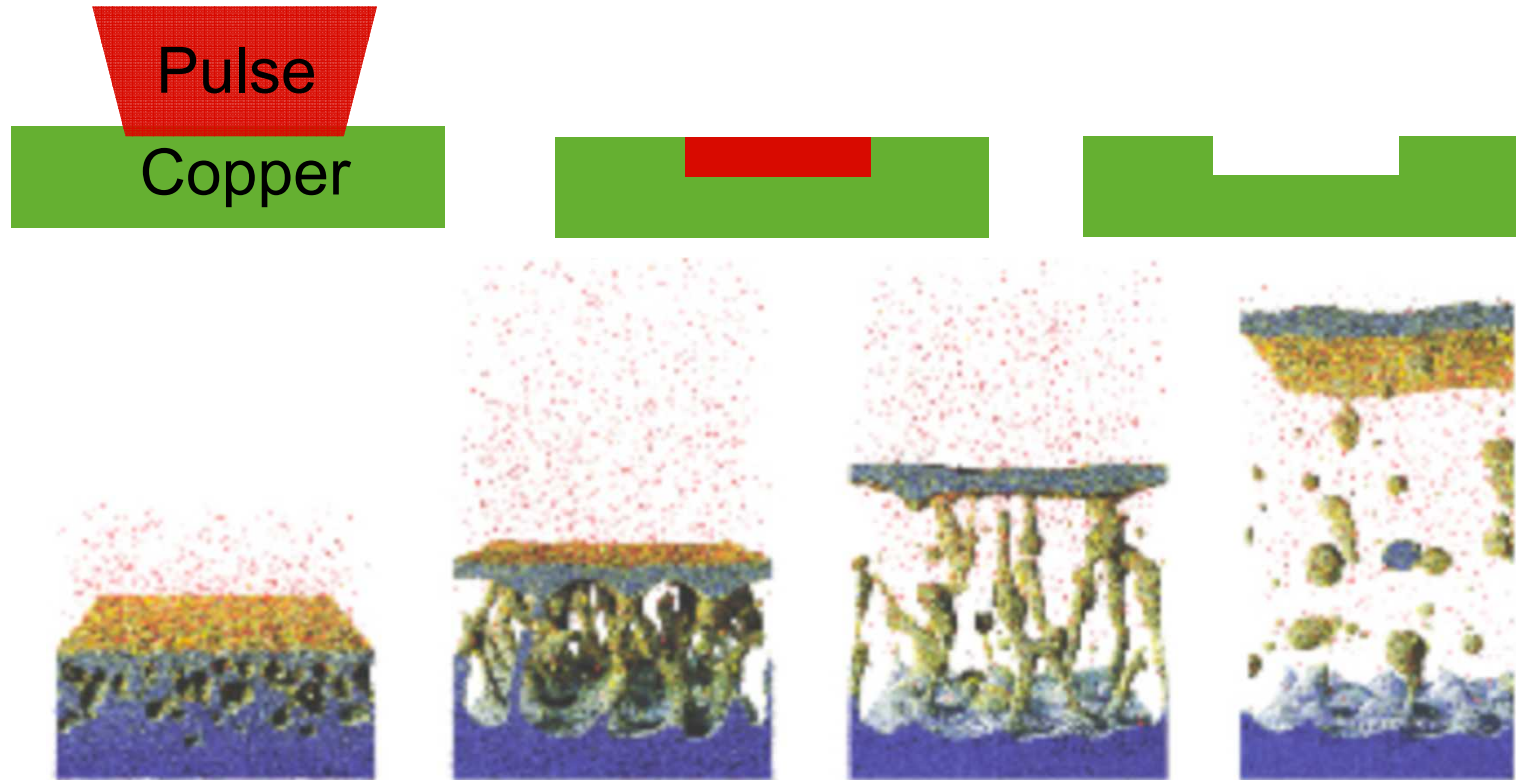
We have applied a nanoparticle laser-printing technique to energetic materials using CL-20 film lift-off from glass substrates after ultrafast (~ 50 fs pulse length) irradiation in air. Unique interactions of ultrafast laser pulses with the thin film energetic material allow for the deposition of micron-scale and nanoparticles onto glass substrates. Control over printed particles, such as the printed distribution, is achieved by changing the laser fluence and film-substrate distance. We demonstrate $2.8\text{ }\mu\text{m}$ CL-20 film removal from substrates resulting in rapid particle printing in air. Particles are printed and then characterized using optical and electron microscopy. Future work will also be discussed.

Outline

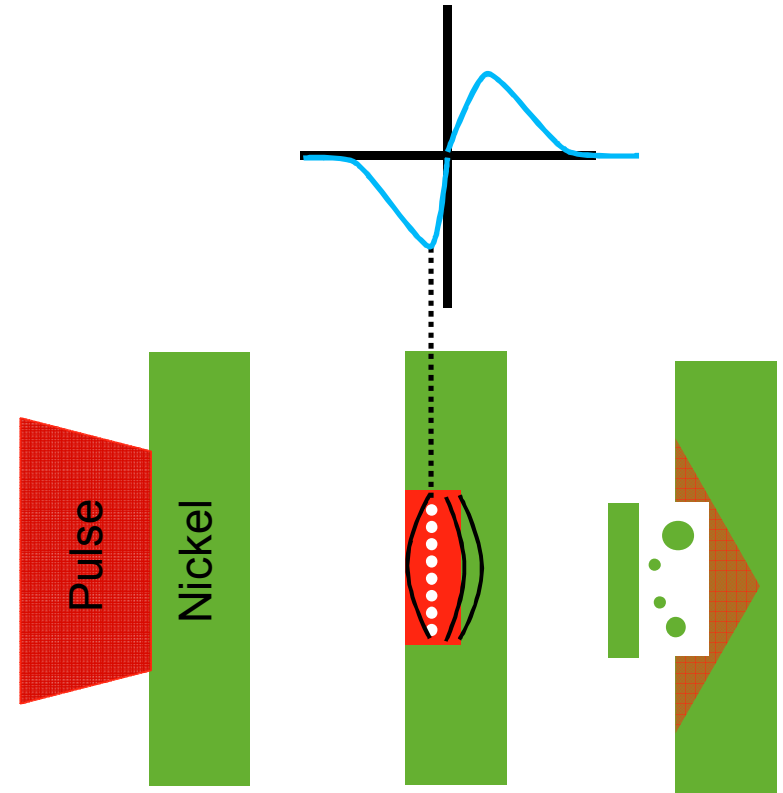
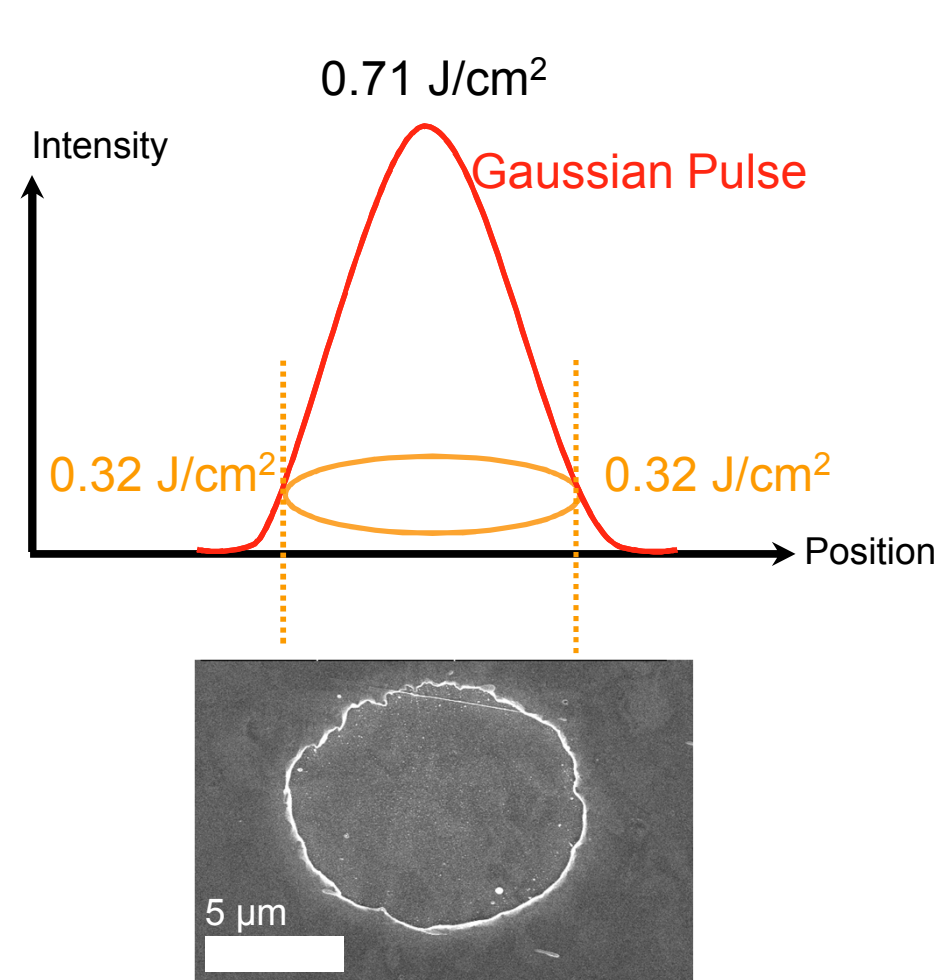
- Background work performed by Ryan Murphy
- Current Setup in the Explosives Component Facility
- Experimental Setup
- Results
- Future Work

Ultrafast Laser Damage in Bulk Materials

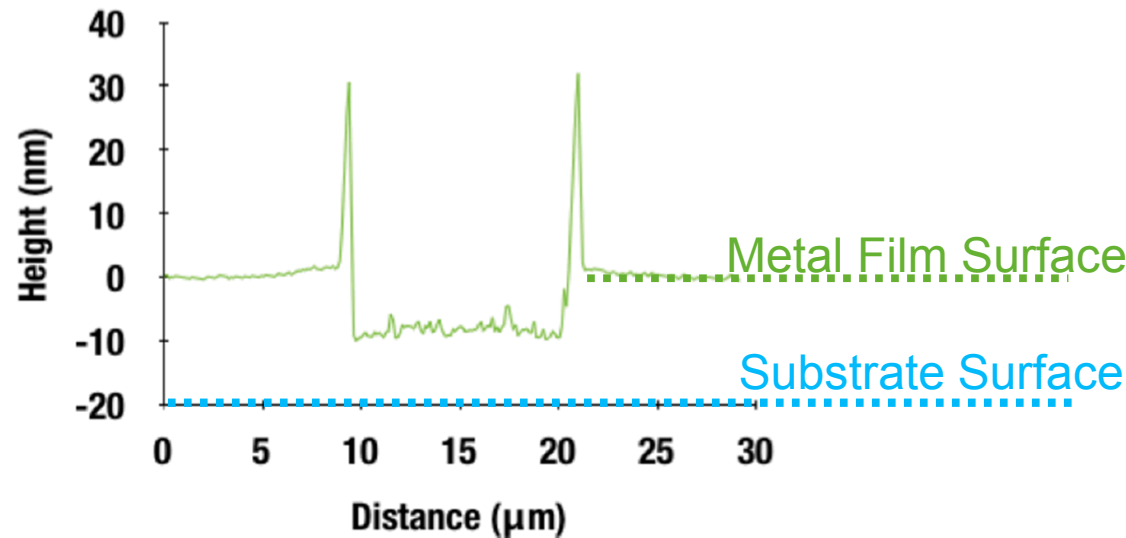
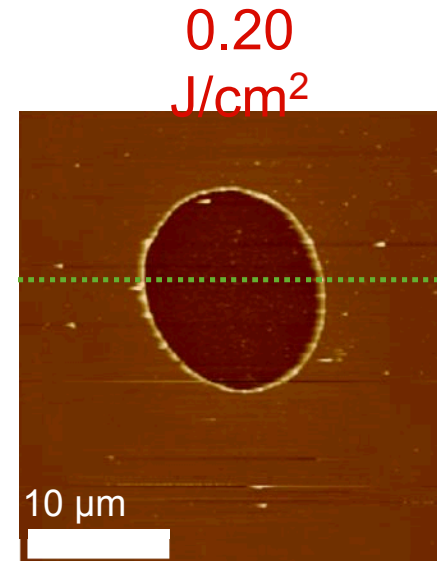
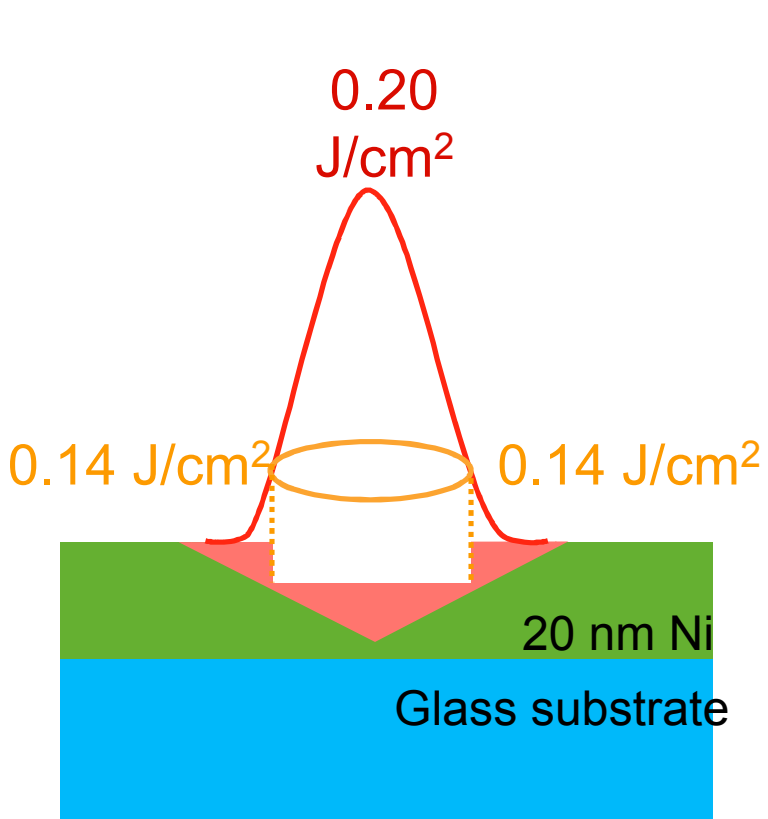
- First few nanometers of material melts in ~ 3 ps.
- Rapid expansion leads to homogeneous void nucleation within melt.
- Material “breaks” where voids nucleate.



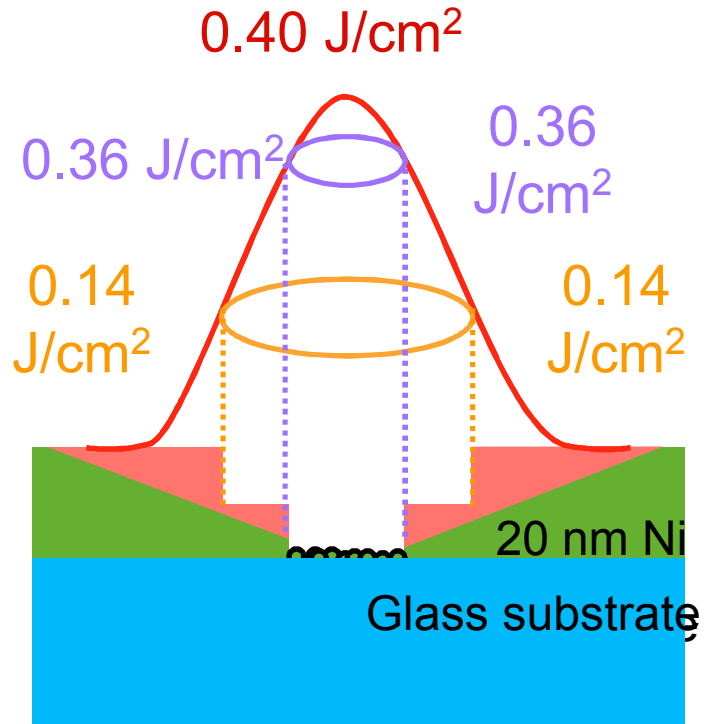
Deterministic Thresholds



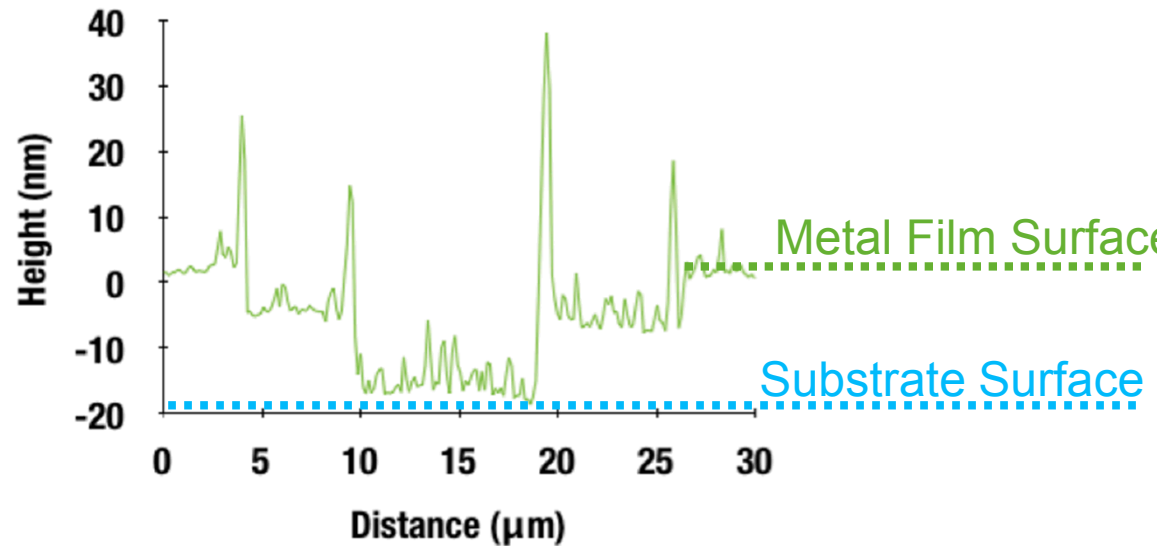
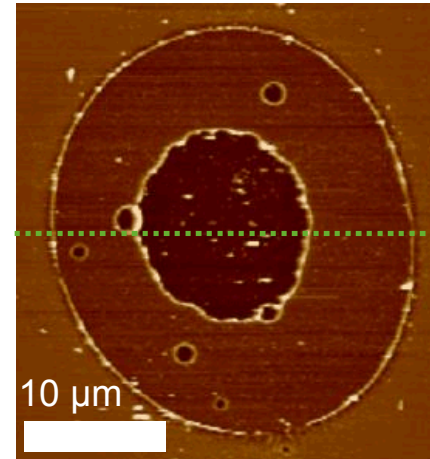
Low Fluence Removal Within Film



High Fluence Removal Within Film + at Interface

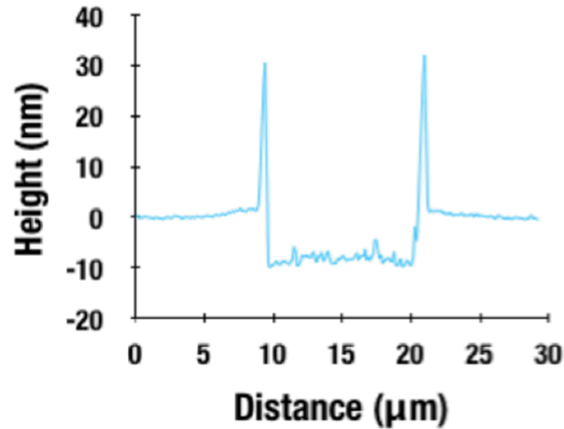
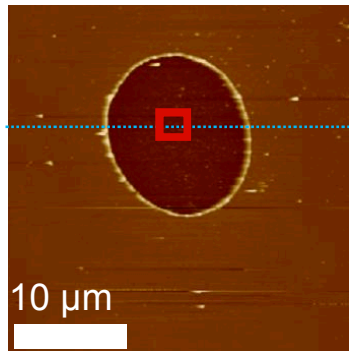


0.40 J/cm²

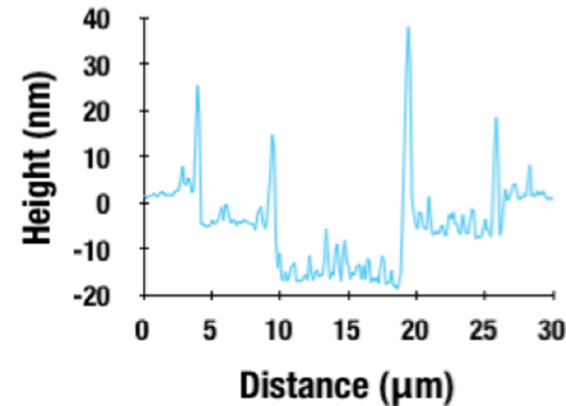
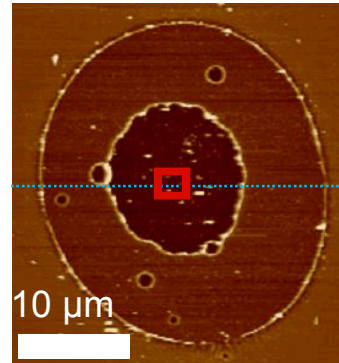


Void Nucleation Controls Surface Roughness

0.20 J/cm²

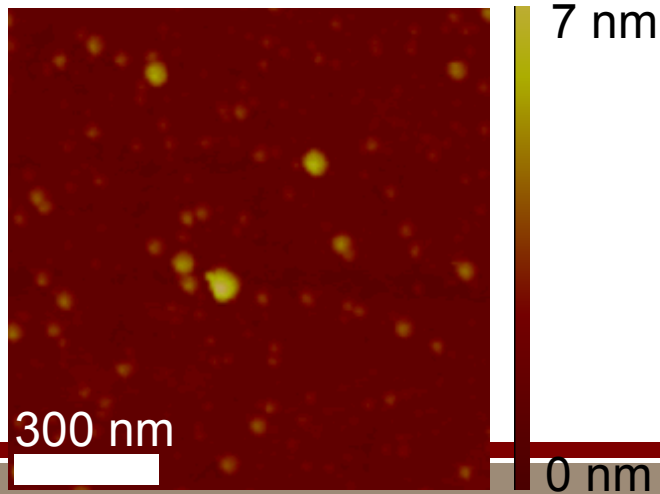


0.40 J/cm²



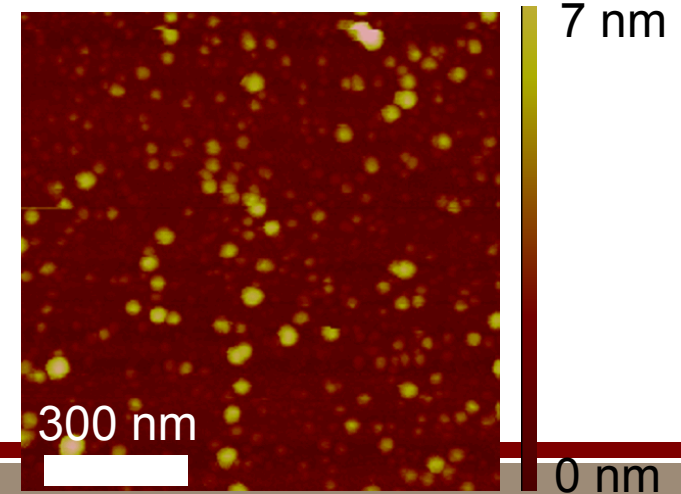
Intra-film Separation

RMS Roughness = 1.27 nm

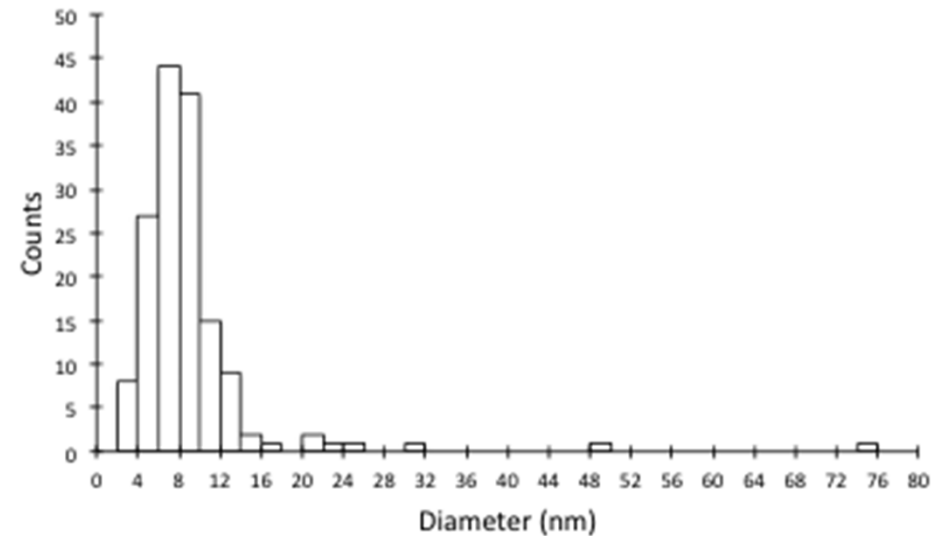
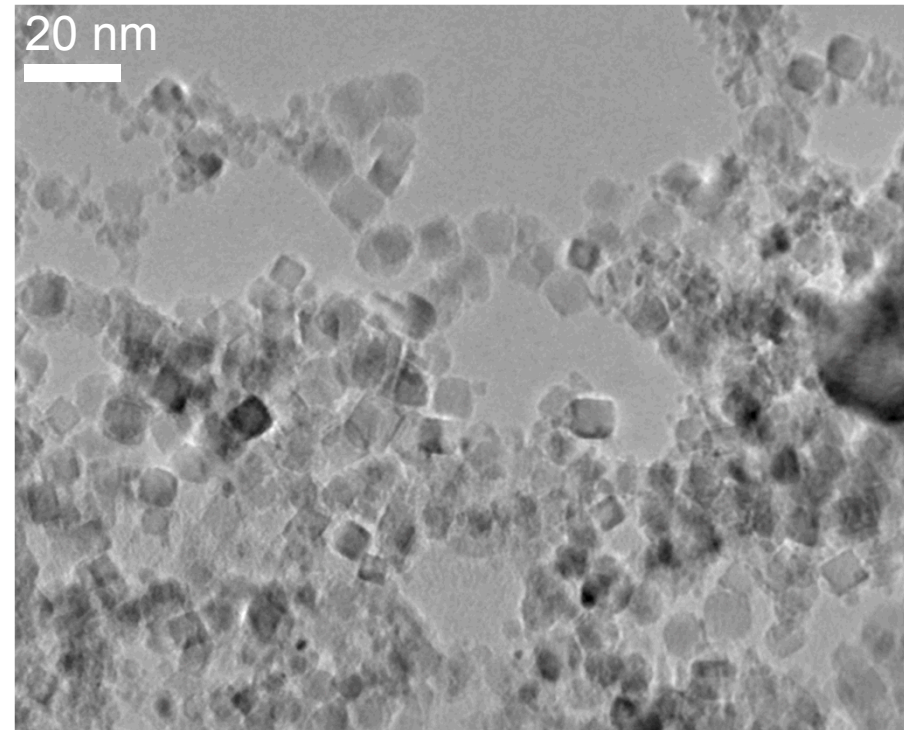
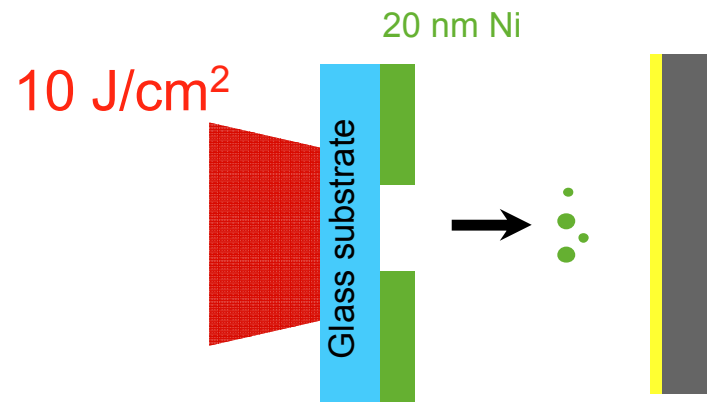


Interface Separation

RMS Roughness = 3.06 nm



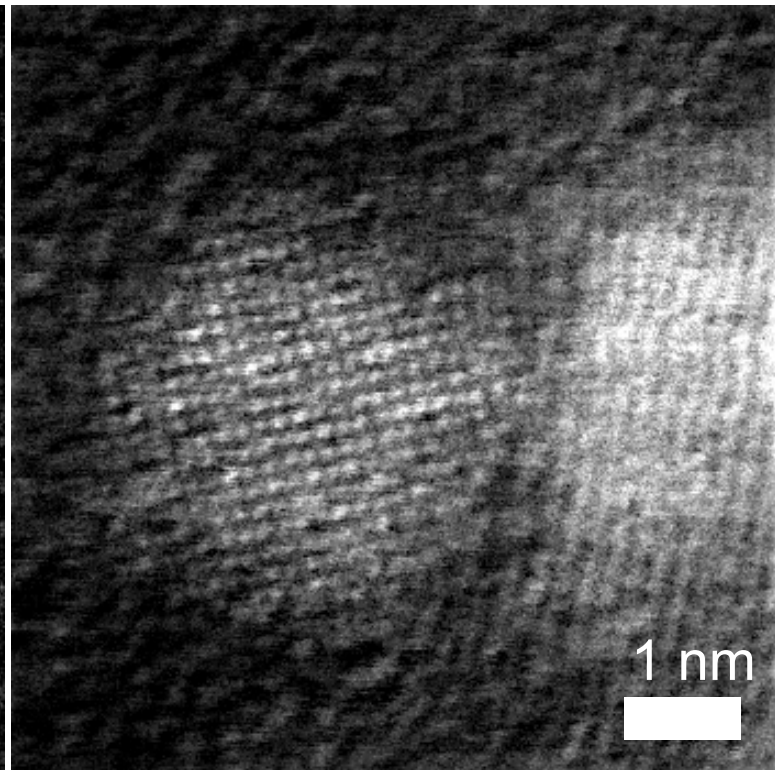
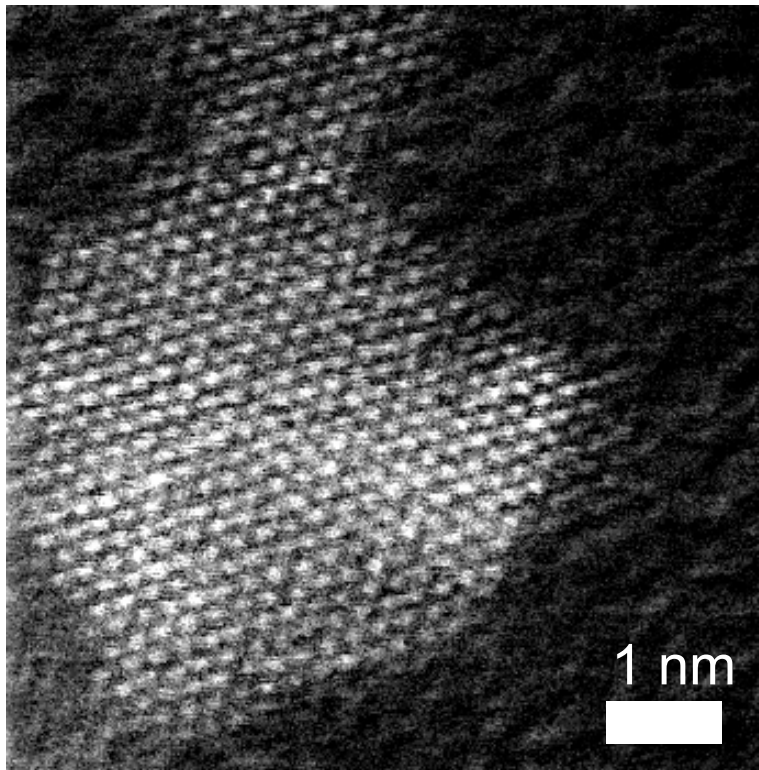
Ni Nanoparticle Printing



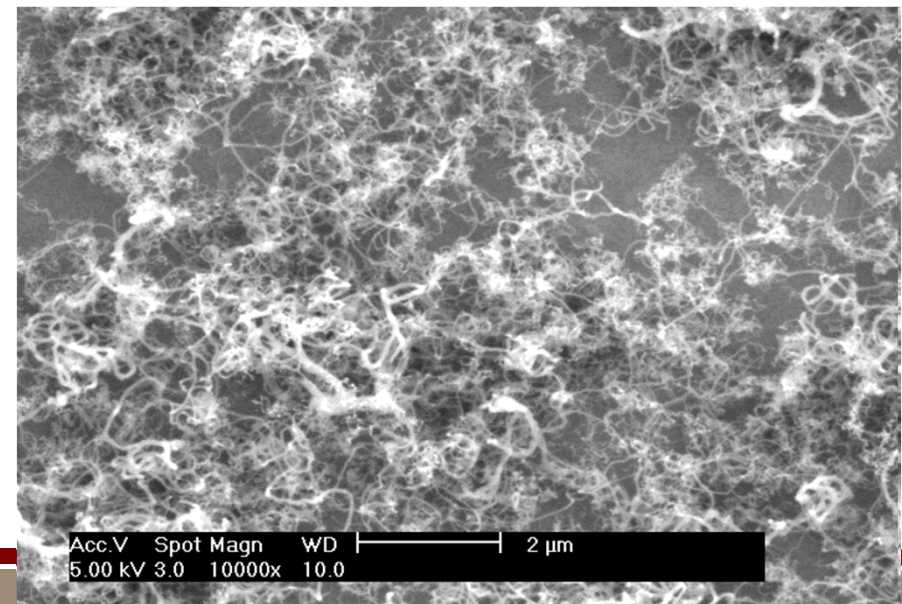
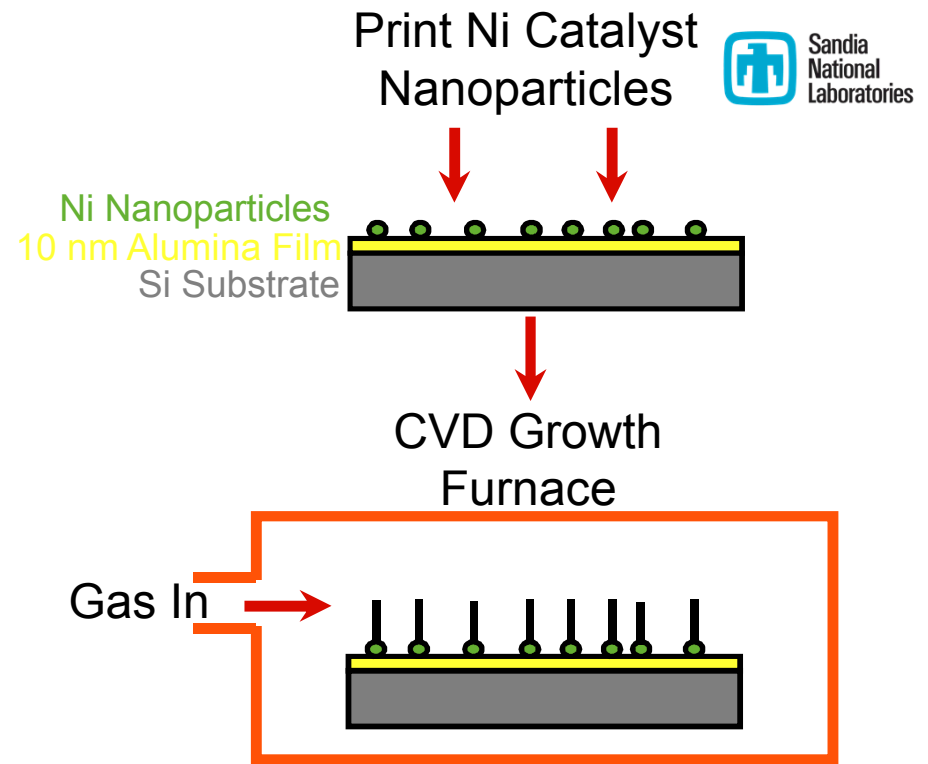
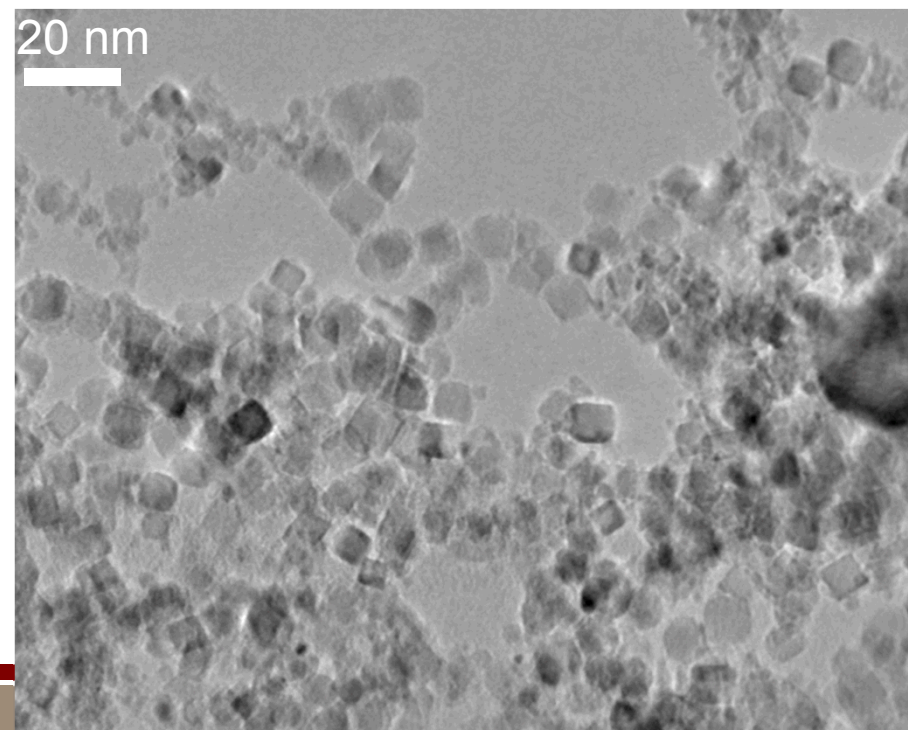
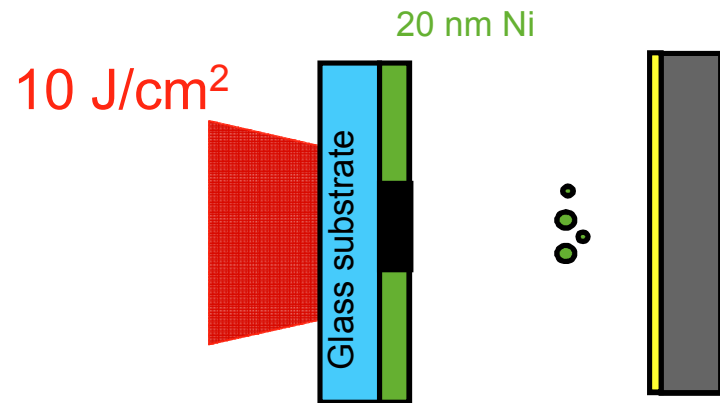
- Can we pattern surfaces with energetic materials using laser ablation?

Faceted Nanoparticles

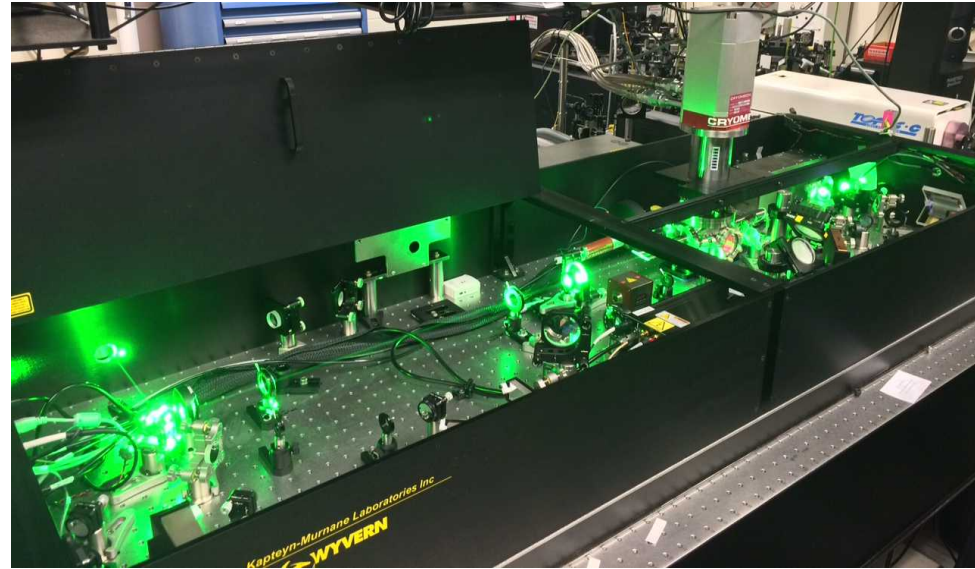
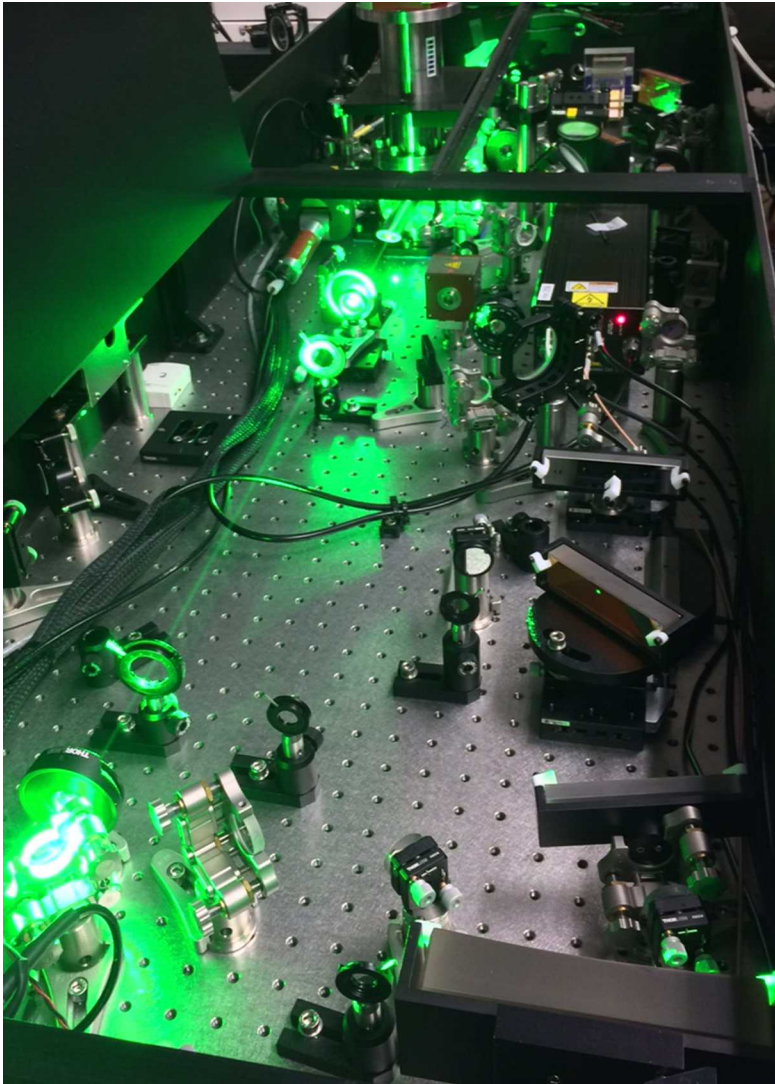
Atomic Resolution



Ni Nanoparticle Printing



Laser Setup ECF



Laser Parameters

4 mJ

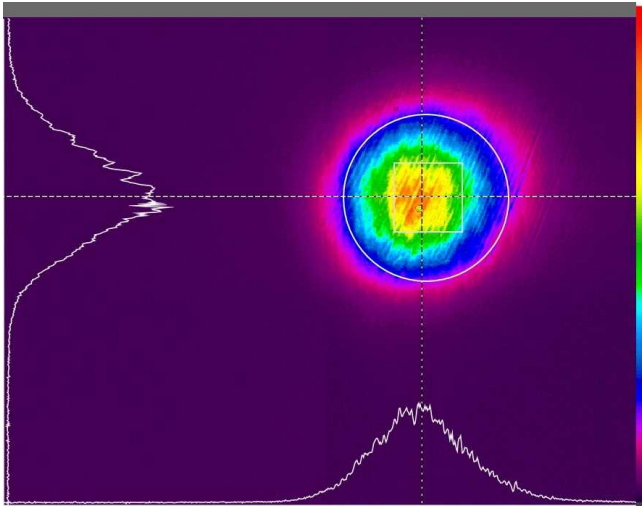
1 kHz (Single shot capable)

40 fs pulse width

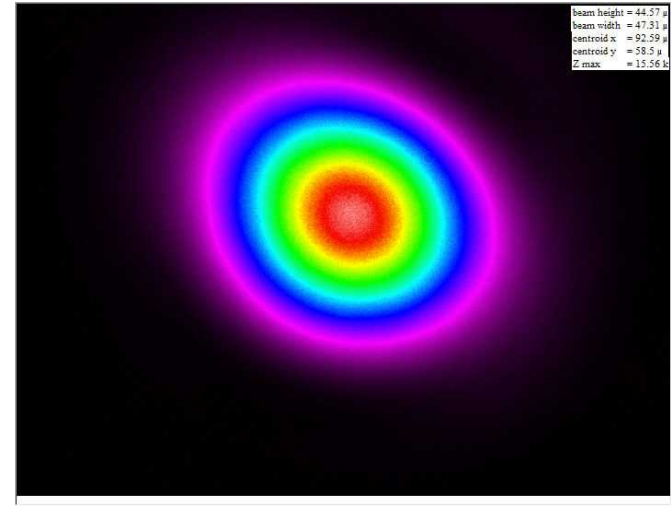
35 nm bandwidth

785 nm center wavelength

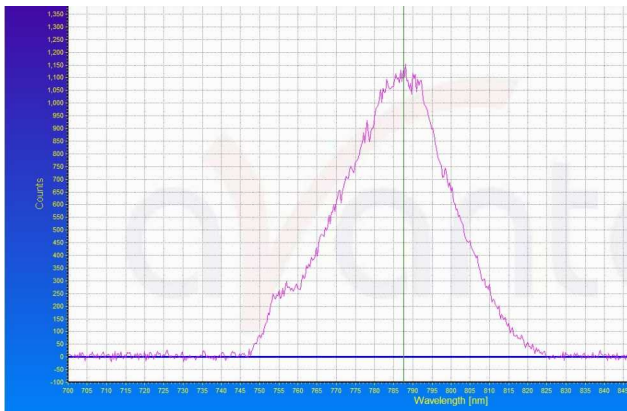
Laser Setup Diagnostics



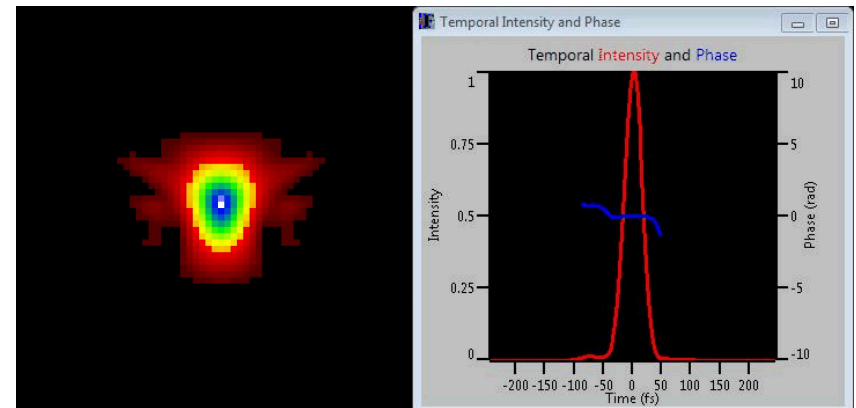
Nearfield Camera



Farfield Camera

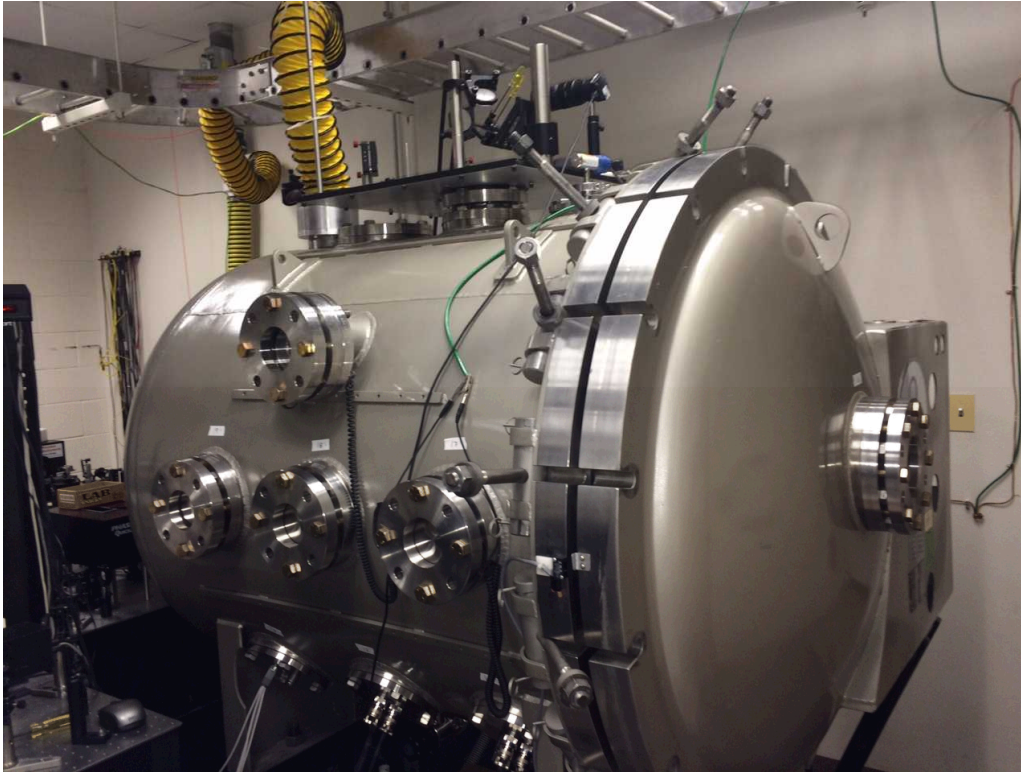


Spectrometer

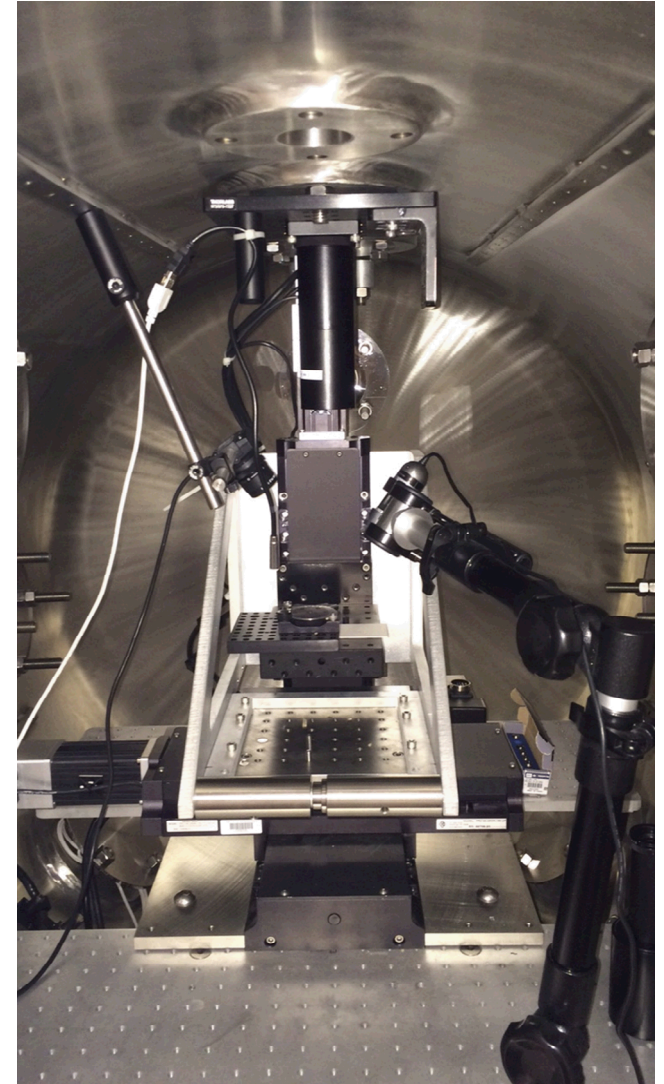


FROG

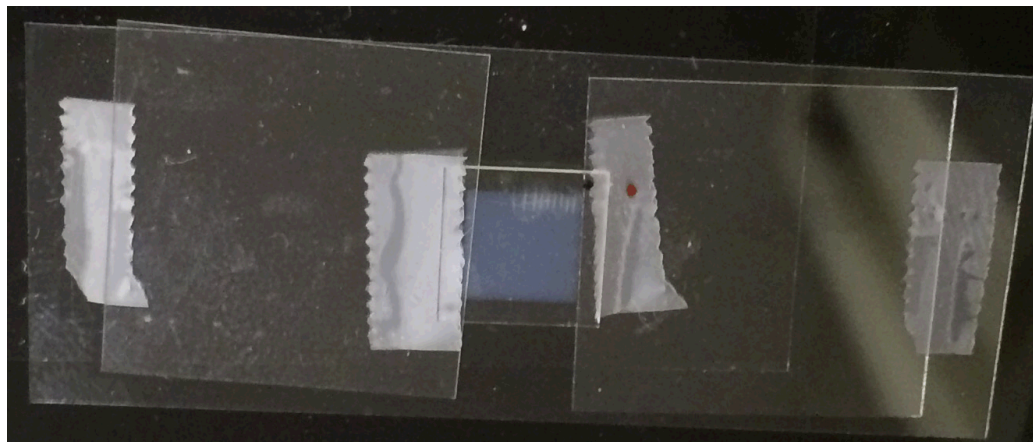
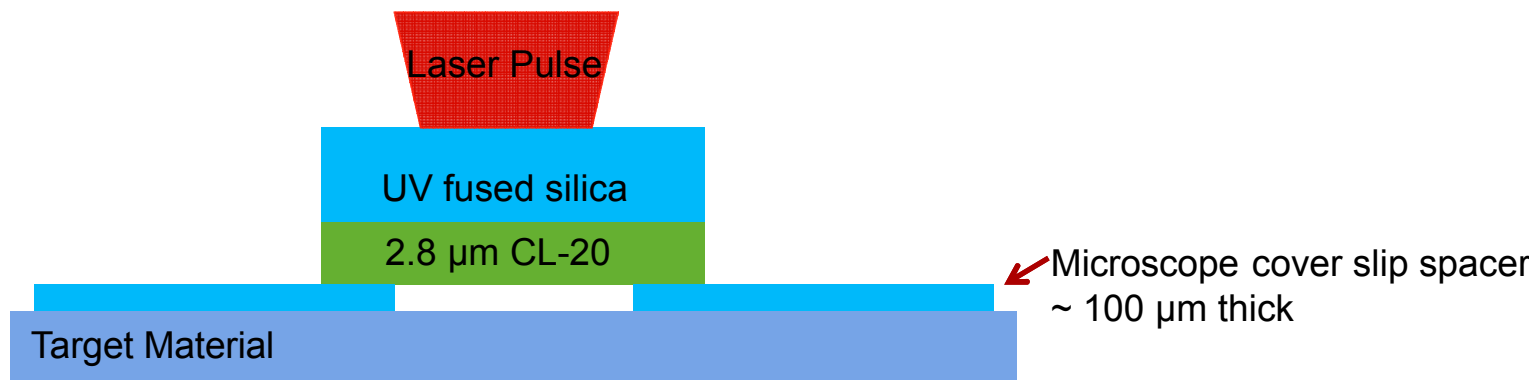
Experimental Setup



Explosives chamber
10g TNT equivalent capacity
Vacuum chamber and full venting
Aerotech 3-D computer controlled
stage
3 cameras for remote viewing



Experimental Setup- Samples



Data Set

- Thin film CL-20 sample (2.8 μm)
- Focusing optic – 200 mm fl lens ($\sim 20\mu\text{m}$ spot size)
- Spacer distance $\sim 100\ \mu\text{m}$ cover slip spacer
- Pulse width $\sim 40\ \text{fs}$ –close to transform limited
- Five energy levels
 - 160 μJ (damaged the target), 80 μJ , 40 μJ , 20 μJ , 15 μJ (ablation threshold)

Results 80 uJ – Optical Microscope

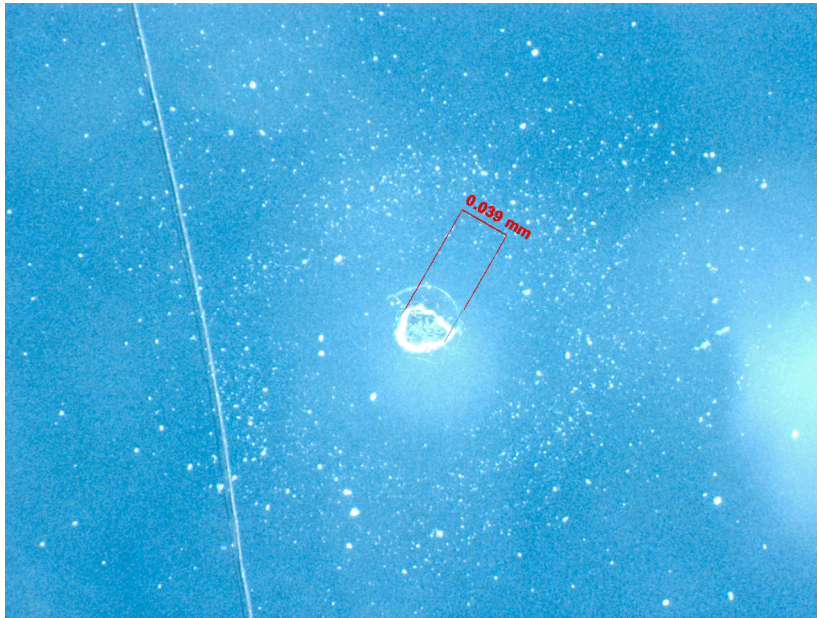


Laser spot profile on CL-20 film
50 μm film spot

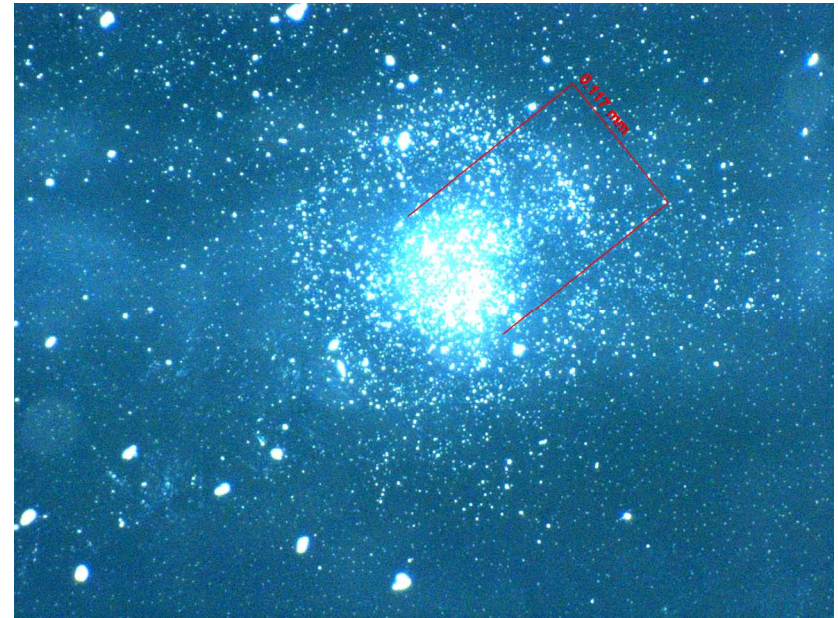


Printed CL-20 particles
~100 μm particle distribution

Results 40 uJ – Optical Microscope

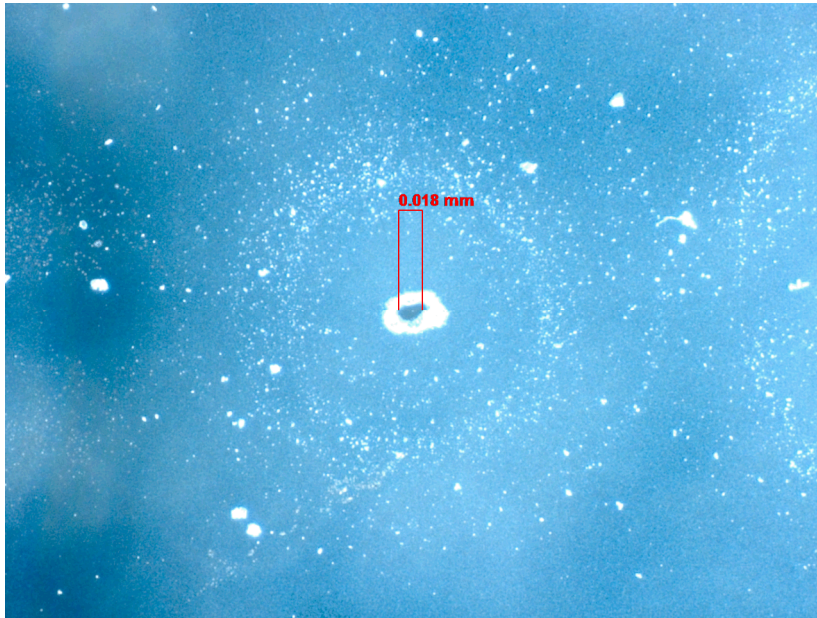


Laser spot profile on CL-20 film
40 μm film spot



Printed CL-20 particles
~100 μm particle distribution

Results 20 uJ – Optical Microscope



Laser spot profile on CL-20 film
18 μm film spot



Printed CL-20 particles
~70 μm particle distribution

Results 15 uJ – Optical Microscope

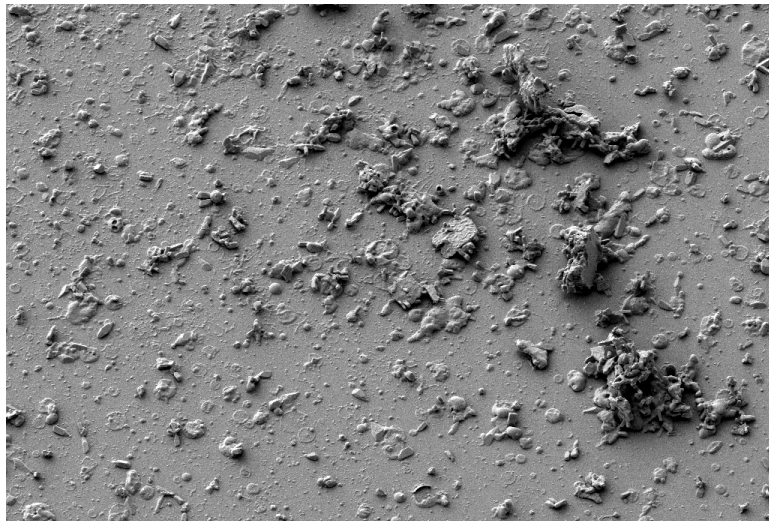


Laser spot profile on CL-20 film
17 μm film spot size



Printed CL-20 particles
~70 μm particle distribution

Results 80 μ J – SEM



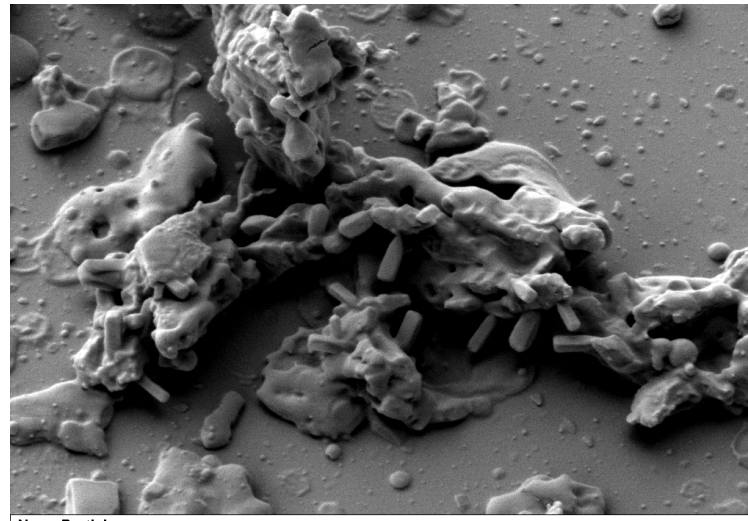
Nano Particles
1-1 80 μ J
File= 1-1_80uj_50um-1.tif

10 μ m

2.29 K X
2.00 kV
SE2

Width = 50.00 μ m
Stage at T = 30.0°
WD = 6.5 mm

17 Sep 2015
Mag> Polaroid 545
3.39e-004 Pa



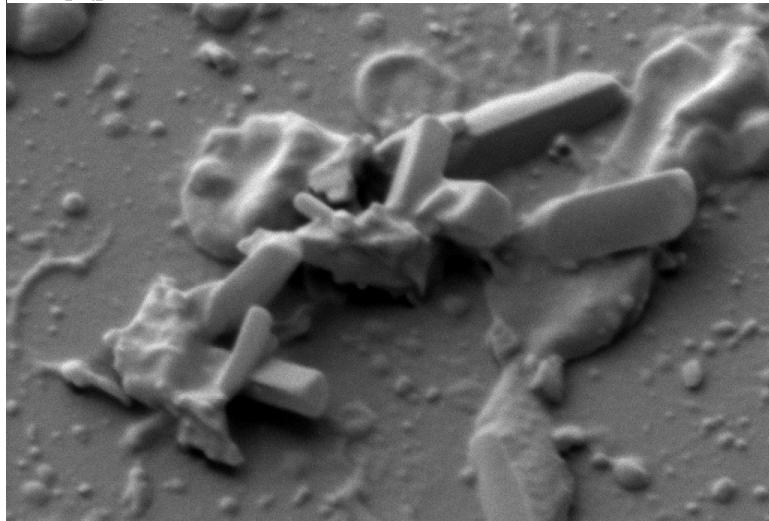
Nano Particles
1-1 80 μ J
File= 1-1_80uj_10um-1.tif

1 μ m

11.43 K X
2.00 kV
SE2

Width = 10.00 μ m
Stage at T = 30.0°
WD = 6.5 mm

17 Sep 2015
Mag> Polaroid 545
3.30e-004 Pa



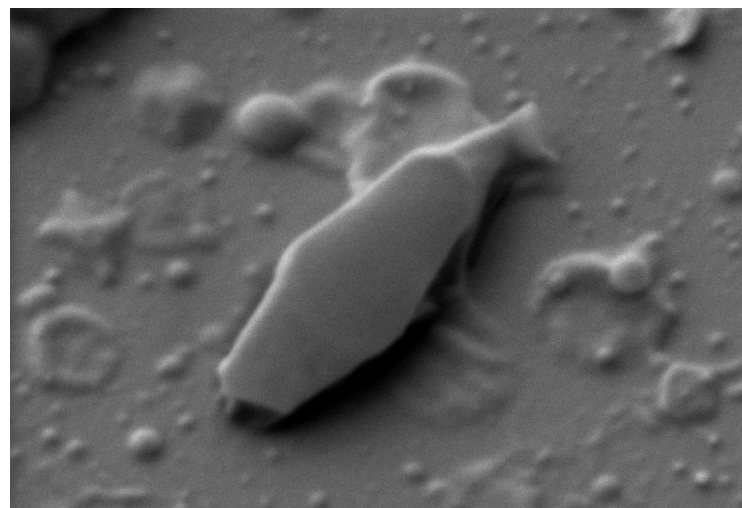
Nano Particles
1-1 80 μ J
File= 1-1_80uj_4um-1.tif

200 nm

28.58 K X
2.00 kV
SE2

Width = 4.000 μ m
Stage at T = 30.0°
WD = 3.9 mm

17 Sep 2015
Mag> Polaroid 545
2.84e-004 Pa



Nano Particles
1-1 80 μ J
File= 1-1_80uj_2p5um-1.tif

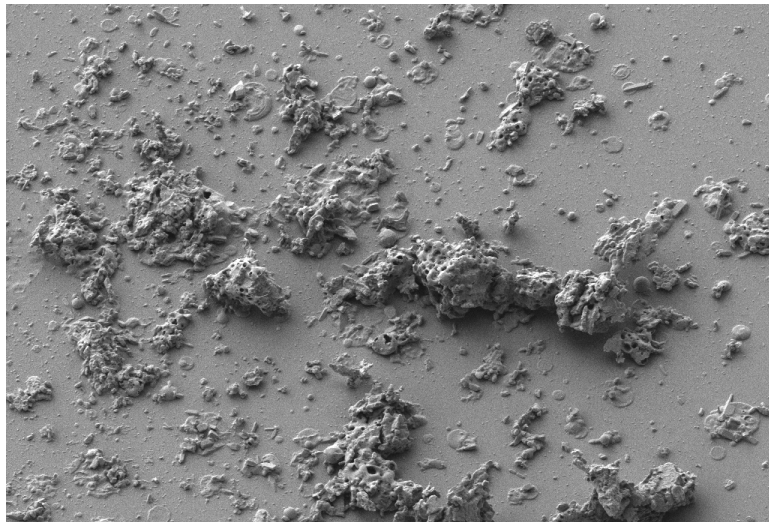
100 nm

45.73 K X
2.00 kV
SE2

Width = 2.500 μ m
Stage at T = 30.0°
WD = 3.9 mm

17 Sep 2015
Mag> Polaroid 545
2.93e-004 Pa

Results 40 μ J – SEM



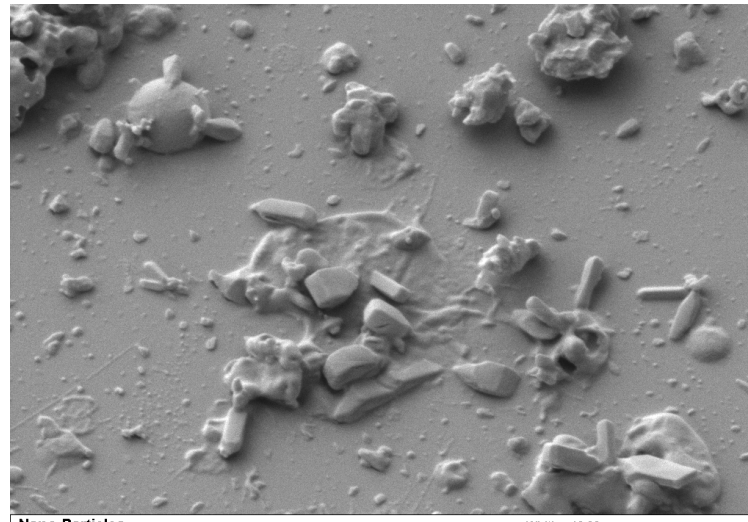
Nano Particles
2-2 40 μ J
File= 2-2_40uj_50um-1.tif

10 μ m

2.29 K X
2.00 kV
SE2

Width = 50.00 μ m
Stage at T = 30.0°
WD = 3.9 mm

17 Sep 2015
Mag> Polaroid 545
2.76e-004 Pa



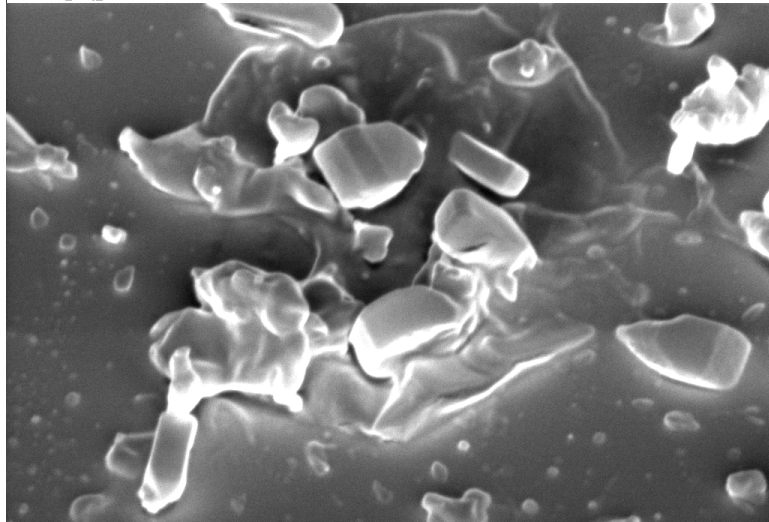
Nano Particles
2-2 40 μ J
File= 2-2_40uj_10um-1.tif

1 μ m

11.43 K X
2.00 kV
SE2

Width = 10.00 μ m
Stage at T = 30.0°
WD = 3.9 mm

17 Sep 2015
Mag> Polaroid 545
2.74e-004 Pa



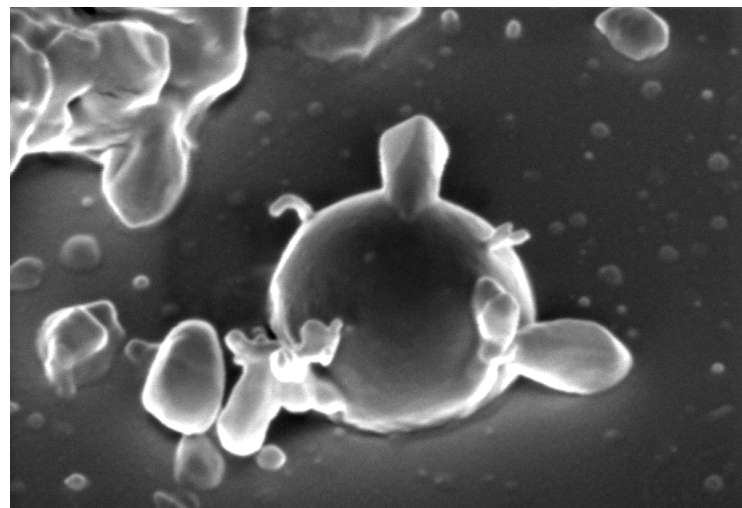
Nano Particles
2-2 40 μ J
File= 2-2_40uj_5um-1.tif

1 μ m

22.87 K X
2.00 kV
InlensDuo

Width = 5.000 μ m
Stage at T = 30.0°
WD = 2.7 mm

17 Sep 2015
Mag> Polaroid 545
2.69e-004 Pa



Nano Particles
2-2 40 μ J
File= 2-2_40uj_3um-1.tif

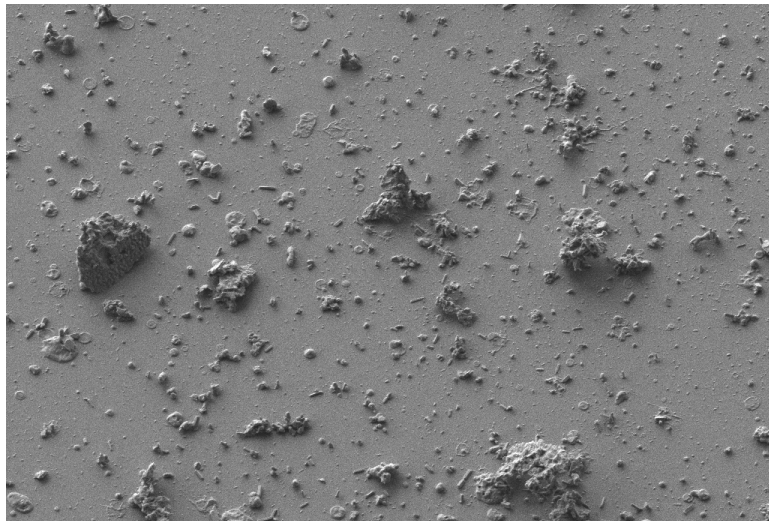
200 nm

37.20 K X
2.00 kV
InlensDuo

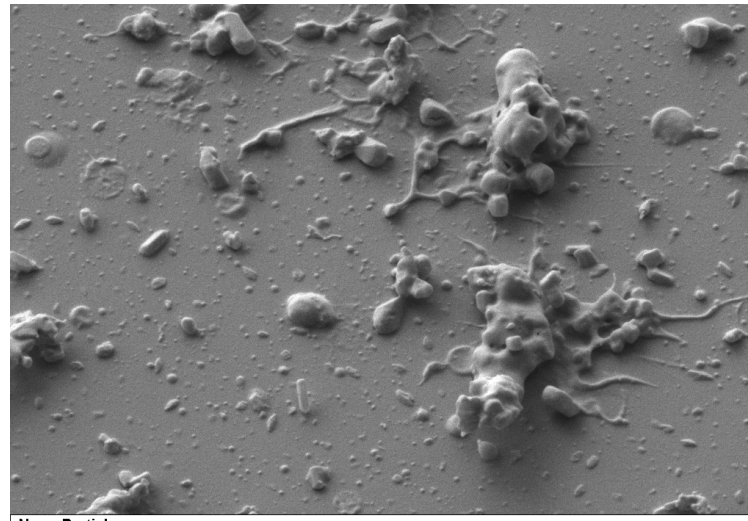
Width = 3.074 μ m
Stage at T = 30.0°
WD = 2.7 mm

17 Sep 2015
Mag> Polaroid 545
2.63e-004 Pa

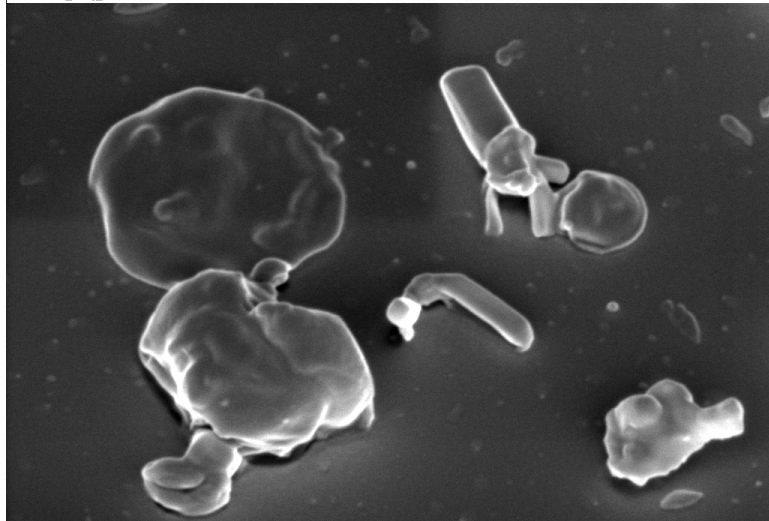
Results 20 μ J – SEM



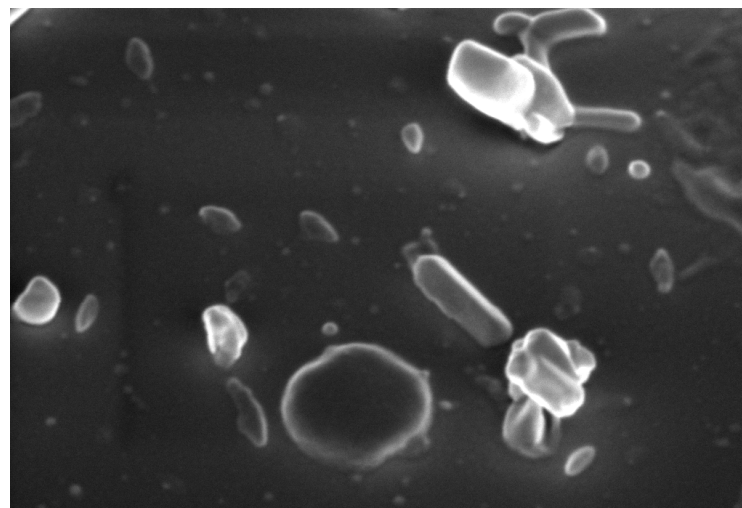
Nano Particles
3-1 20 μ J
File= 3-1_20uj_50um-1.tif
10 μ m
2.29 K X
2.00 kV
SE2
Width = 50.00 μ m
Stage at T = 30.0°
WD = 2.1 mm
17 Sep 2015
Mag> Polaroid 545
2.53e-004 Pa



Nano Particles
3-1 20 μ J
File= 3-1_20uj_10um-1.tif
1 μ m
11.43 K X
2.00 kV
SE2
Width = 10.00 μ m
Stage at T = 30.0°
WD = 2.1 mm
17 Sep 2015
Mag> Polaroid 545
2.42e-004 Pa

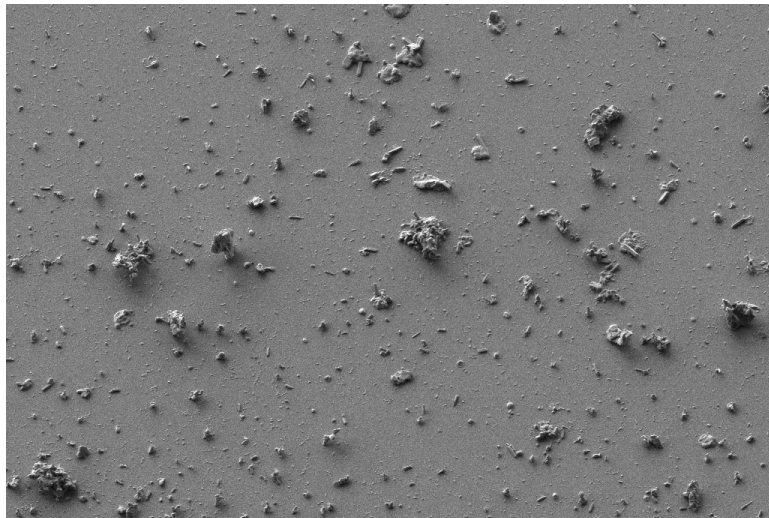


Nano Particles
3-1 20 μ J
File= 3-1_20uj_4um-1.tif
200 nm
28.58 K X
2.00 kV
InlensDuo
Width = 4.000 μ m
Stage at T = 30.0°
WD = 2.1 mm
17 Sep 2015
Mag> Polaroid 545
2.49e-004 Pa

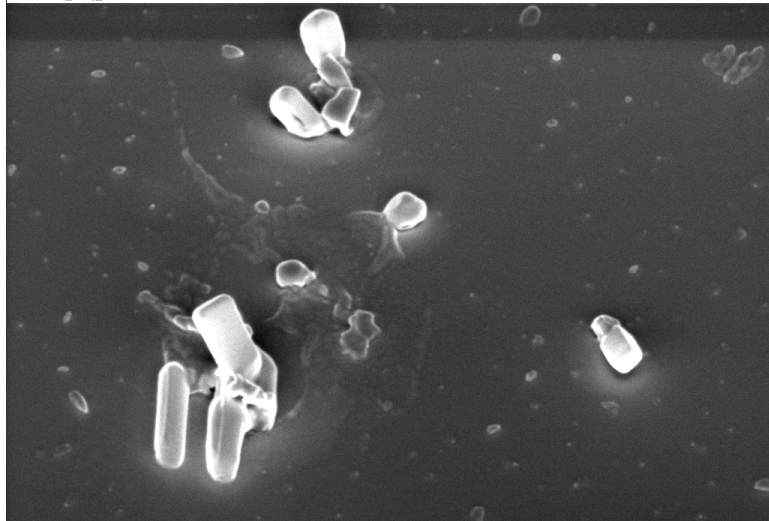


Nano Particles
3-1 20 μ J
File= 3-1_20uj_3um-1.tif
200 nm
38.11 K X
2.00 kV
InlensDuo
Width = 3.000 μ m
Stage at T = 30.0°
WD = 2.1 mm
17 Sep 2015
Mag> Polaroid 545
2.45e-004 Pa

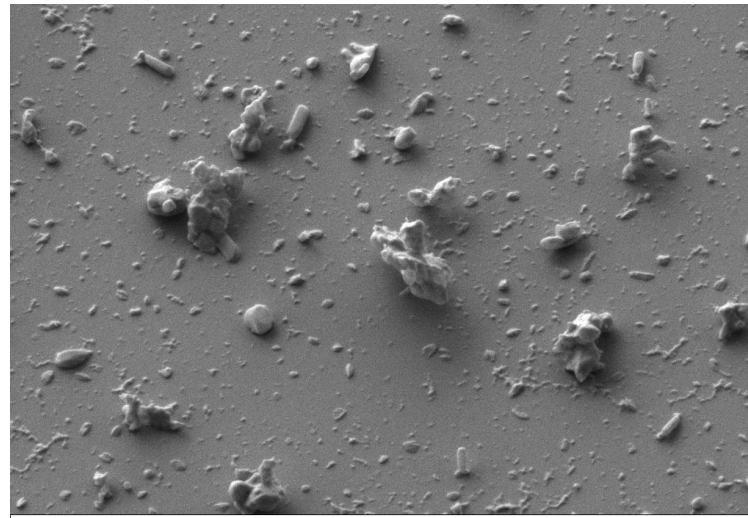
Results 15 μ J – SEM



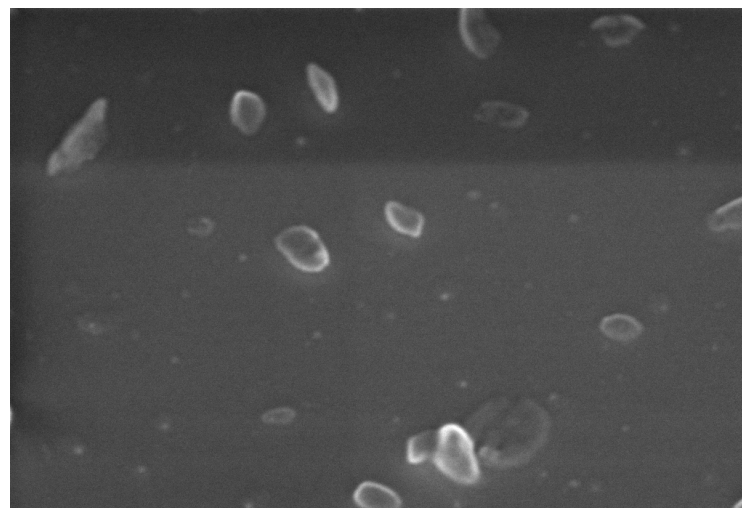
Nano Particles
4-1 15 μ J
File= 4-1_15uj_50um-1.tif
10 μ m
2.29 K X
2.00 kV
SE2
Width = 50.00 μ m
Stage at T = 30.0°
WD = 2.1 mm
Mag> Polaroid 545
17 Sep 2015
2.40e-004 Pa



Nano Particles
4-1 15 μ J
File= 4-1_15uj_5um-1.tif
1 μ m
22.87 K X
2.00 kV
InlensDuo
Width = 5.000 μ m
Stage at T = 30.0°
WD = 2.1 mm
Mag> Polaroid 545
17 Sep 2015
2.31e-004 Pa



Nano Particles
4-1 15 μ J
File= 4-1_15uj_10um-1.tif
1 μ m
11.43 K X
2.00 kV
SE2
Width = 10.000 μ m
Stage at T = 30.0°
WD = 2.1 mm
Mag> Polaroid 545
17 Sep 2015
2.37e-004 Pa



Nano Particles
4-1 15 μ J
File= 4-1_15uj_2-5um-1.tif
200 nm
45.73 K X
2.00 kV
InlensDuo
Width = 2.500 μ m
Stage at T = 30.0°
WD = 2.1 mm
Mag> Polaroid 545
17 Sep 2015
2.33e-004 Pa

Results- Discussion

- Too high energy damages the target material
- High fluence appears to give larger particle agglomeration
- Generating particles close to the ablation threshold appears to give a more uniform particle size distribution

Future Work

- Changing film thickness has shown with other materials to influence nanoparticle size. We would like to investigate using multiple film thickness samples
- Stand off and focusing geometry both contribute to the macro deposited spot. Would like to investigate different geometries.
 - As part of this we would like to pursue printing different features including continuous lines
- All work was done at a fixed pulse width ~ 40 fs. Would like to investigate chirping the pulse
- All work was done at 785 nm. Other work shows more efficient ablation closer to the UV. Could frequency double the light.

Future Work - Cont

- Analysis was limited to optical microscope and SEM. We plan on doing TEM measurements to validate that no changes were made to the energetic material. X-ray diffraction measurements are also a possibility.